Search Notes		

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
09/774,074	FAN, JIAN	
Examiner	Art Unit	
Stephen M. Brinich	2624	

SEARCHED				
Class	Subclass	Date	Examiner	
358	261.3- 261.4, 1.15, 450	5/24/2005	SMB	
358	540, 426	5/24/2005	SMB	
358	432-433	5/24/2005	SMB	
358	500, 518	5/24/2005	SMB	
358	456, 539	5/24/2005	SMB	
395	114-117	5/24/2005	SMB	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST	5/24/2005	SMB
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